Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/659,101	CHAN ET AL.	
Examiner	Art Unit	
Randall Chin	1744	

SEARCHED				
Class	Subclass	Date	Examiner	
15	143.1	1	l	
15	167.1	8/1/2005	RC	
15	22.1			
UPPATE	D SEMLET	3/5/06	pe	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor name search	8/1/2005	RC	
	·		